

**Integrated circuits - Measurement of electromagnetic emissions - Part 8: Measurement of radiated emissions - IC stripline method**

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## EESTI STANDARDI EESSÕNA

## NATIONAL FOREWORD

Käesolev Eesti standard EVS-EN 61967-8:2011 sisaldab Euroopa standardi EN 61967-8:2011 ingliskeelset teksti.

Standard on kinnitatud Eesti Standardikeskuse 31.10.2011 käskkirjaga ja jõustub sellekohase teate avaldamisel EVS Teatajas.

Euroopa standardimisorganisatsioonide poolt rahvuslikele liikmetele Euroopa standardi teksti kättesaadavaks tegemise kuupäev on 14.10.2011.

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This Estonian standard EVS-EN 61967-8:2011 consists of the English text of the European standard EN 61967-8:2011.

This standard is ratified with the order of Estonian Centre for Standardisation dated 31.10.2011 and is endorsed with the notification published in the official bulletin of the Estonian national standardisation organisation.

Date of Availability of the European standard text 14.10.2011.

The standard is available from Estonian standardisation organisation.

ICS 31.200

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**Integrated circuits -  
Measurement of electromagnetic emissions -  
Part 8: Measurement of radiated emissions -  
IC stripline method  
(IEC 61967-8:2011)**

Circuits intégrés -  
Mesure des émissions  
électromagnétiques -  
Partie 8: Mesure des émissions  
rayonnées -  
Méthode de la ligne TEM à plaques  
(stripline) pour CI  
(CEI 61967-8:2011)

Integrierte Schaltungen -  
Messung von elektromagnetischen  
Aussendungen -  
Teil 8: Messung der abgestrahlten  
Aussendungen -  
IC-Streifenleiterverfahren  
(IEC 61967-8:2011)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
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## Foreword

The text of document 47A/868/FDIS, future edition 1 of IEC 61967-8, prepared by SC 47A, "Integrated circuits", of IEC TC 47, "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61967-8:2011.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2012-06-15
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2014-09-15

This standard is to be used in conjunction with EN 61967-1.

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## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-131	-	International Electrotechnical Vocabulary (IEV) - Part 131: Circuit theory	-	-
IEC 60050-161	-	International Electrotechnical Vocabulary (IEV) - Chapter 161: Electromagnetic compatibility	-	-
IEC 61000-4-20	-	Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides	EN 61000-4-20	-
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 61967-1	-
IEC 61967-2	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 2: Measurement of radiated emissions - TEM cell and wideband TEM cell method	EN 61967-2	-

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## INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –

### Part 8: Measurement of radiated emissions – IC stripline method

#### 1 Scope

The measurement procedure of this part of IEC 61967 defines a method for measuring the electromagnetic radiated emission from an integrated circuit (IC) using an IC stripline in the frequency range of 150 kHz up to 3 GHz. The IC being evaluated is mounted on an EMC test board (PCB) between the active conductor and the ground plane of the IC stripline arrangement.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-131: *International Electrotechnical Vocabulary (IEV) – Part 131: Circuit theory*

IEC 60050-161: *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

IEC 61967-1: *Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz – Part 1: General conditions and definitions*

IEC 61967-2: *Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz – Part 2: Measurement of radiated emissions – TEM cell and wideband TEM cell method*

IEC 61000-4-20: *Electromagnetic compatibility (EMC) – Part 4-20: Testing and measurement techniques – Emission and immunity testing in transverse electromagnetic (TEM) waveguides*

#### 3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 61967-1, IEC 60050-131 and IEC 60050-161 as well as the following apply.

##### 3.1

##### **transverse electromagnetic (TEM) mode**

waveguide mode in which the components of the electric and magnetic fields in the propagation direction are much less than the primary field components across any transverse cross-section

##### 3.2

##### **TEM waveguide**

open or closed transmission line system, in which a wave is propagating in the transverse electromagnetic mode to produce a specified field for testing purposes